



2019 IEDM Conference Theme
**Innovative Devices for an Era
of Connected Intelligence**



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2019 IEEE International Electron Devices Meeting

December 7th – 11th, 2019

Hilton San Francisco Union Square
San Francisco, California

Focused Call for Papers

IEDM is pleased to announce increased technical focus in the area of:

Reliability of Systems and Devices (RSD)

Topics

Papers are solicited in the following themes of interest:

- Reliability of FEOL/MEOL/BEOL, latch-up and ESD;
- Reliability and variability-aware design
- Robustness and security of electronic circuits and systems
- Reliability of devices and systems for biomedical, automotive and aerospace

New or trending areas include:

- Degradation mechanisms of emerging memories
- Reliability of devices, circuits and systems for more-than-Moore
- Security and reliability of circuits and systems for the IoT
- Reliability of wide bandgap (SiC, GaN) circuits and systems

Streamlined Paper Submission

Submission deadline: July 26th
Single submission of final, four-page paper